

### SLOVENSKI STANDARD oSIST prEN IEC 62321-14:2025

01-april-2025

Določevanje posameznih snovi v elektrotehničnih izdelkih - 14. del: Določevanje kloriranih parafinov (SCCP) s kratko verigo in kloriranih parafinov s srednje dolgo verigo (MMCCP) v elektrotehničnih izdelkih s plinsko kromatografijo - negativno kemijsko ionizacijo - masno spektrometrijo (GC-NCI-MS)

Determination of certain substances in electrotechnical products - Part 14: Determination of short-chain chlorinated paraffins (SCCPs) and medium-chain chlorinated paraffins (MCCPs) in electrotechnical products by gas chromatography-negative chemical ionization-mass spectrometry (GC-NCI-MS)

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DÉTERMINATION DE CERTAINES SUBSTANCES DANS LES PRODUITS ÉLECTROTECHNIQUES - Partie 14: Détermination des paraffines chlorées à chaîne courte (PCCC) et des paraffines chlorées à chaîne moyenne (PCCM) dans des produits électrotechniques par chromatographie en phase gazeuse couplée à la spectrométrie de masse avec ionisation chimique négative (GC-NCI-MS)

Ta slovenski standard je istoveten z: prEN IEC 62321-14:2025

#### ICS:

13.020.01	Okolje in varstvo okolja na splošno	Environment and environmental protection in general
43.040.10	Električna in elektronska oprema	Electrical and electronic equipment

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### 111/802/CDV

#### COMMITTEE DRAFT FOR VOTE (CDV)

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IEC TC 111 : ENVIRONMENTAL STANDARDIZATION FOR ELECTRICA	L AND ELECTRONIC PRODUCTS AND SYSTEMS
Secretariat:	SECRETARY:
Italy	Mr Alfonso Sturchio
OF INTEREST TO THE FOLLOWING COMMITTEES:	HORIZONTAL FUNCTION(S):
TC 2,TC 9,TC 18,TC 20,TC 21,TC 23,TC 34,SC 34D,TC 59,TC 62,SC 65B,TC 80,TC 82,TC 88,TC 91,TC 100,TC 110,TC 121,TC 124,TC 125	TC 111 Horizontal Basic Environment - Assessment
ASPECTS CONCERNED:	tiluarus
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SUBMITTED FOR CENELEC PARALLEL VOTING	NOT SUBMITTED FOR CENELEC PARALLEL VOTING
Attention IEC-CENELEC parallel voting	t Preview
The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting.	<u>- 262321-14:2025</u> d-4062-a360-c000349349ca/osist-pren-iec-62321-14-1
The CENELEC members are invited to vote through the	

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#### TITLE:

DETERMINATION OF CERTAIN SUBSTANCES IN ELECTROTECHNICAL PRODUCTS – Part 14: Determination of short-chain chlorinated paraffins (SCCPs) and medium-chain chlorinated paraffins (MCCPs) in electrotechnical products by gas chromatography-negative chemical ionization-mass spectrometry (GC-NCI-MS)

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#### PROPOSED STABILITY DATE: 2029

#### NOTE FROM TC/SC OFFICERS:

TC 111 WG 3 confirmed that this CDV document met the two criteria to skip the second IIS approved by NCs (111/777/RQ).

- The first IIS is performed according to the IIS minimum requirements

- There are no significant technical changes in the standard

Based on the agreement at the TC 111 WG 3 meeting held on November 12, 2024, in Okayama, the CDV will be circulated.

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100 101	Fu on	Il information on the votin voting indicated in the at	ng for the approval of thi pove table.	s International Standar	d can be found in the report

102 This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

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The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

106	<ul> <li>reconfirmed,</li> </ul>
107	– withdrawn,
108	<ul> <li>replaced by a revised edition, or</li> </ul>
109	– amended.
110	The National Committees are requested to note that for this document the stability date is 20XX
111	THIS TEXT IS INCLUDED FOR THE INFORMATION OF THE NATIONAL COMMITTEES AND WILL BE DELETED AT
112	PUBLICATION STAGE.

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#### INTRODUCTION

The widespread use of electrotechnical products has drawn increased attention to their impact on the environment. In many countries this has resulted in the adoption of regulations affecting wastes, substances and energy use of electrotechnical products.

The use of certain substances (e.g. lead (Pb), cadmium (Cd) and polybrominated diphenyl ethers (PBDEs)) in electrotechnical products is a source of concern in current and proposed regional legislation.

The purpose of the IEC 62321 series is therefore to provide test methods that will allow the electrotechnical industry to determine the levels of certain substances of concern in electrotechnical products on a consistent global basis.

123 This first edition of IEC 62321-14 introduces a new subject covering short-chain chlorinated paraffins 124 (SCCPs) and medium-chain chlorinated paraffins (MCCPs) in the IEC 62321 series.

125 WARNING — Persons using this International Standard should be familiar with normal laboratory

practice. This International Standard does not purport to address all of the safety problems, if any,

associated with its use. It is the responsibility of the user to establish appropriate safety and health

practices and to ensure compliance with any national regulatory conditions.

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#### DETERMINATION OF CERTAIN SUBSTANCES IN ELECTROTECHNICAL PRODUCTS –

# Part 14: Short-chain chlorinated paraffins (SCCPs) and medium-chain chlorinated paraffins (MCCPs) in plastics by gas chromatography-negative chemical ionization-mass spectrometry (GC-NCI-MS)

#### 136 **1** Scope

137 This part of IEC 62321 specifies one technique for the determination of short-chain and medium-chain 138 chlorinated paraffins (SCCPs: C10-C13 and MCCPs: C14-C17) in plastics of electrotechnical products.

This standard specifies a quantitative method for the determination of short-chain and medium-chain chlorinated paraffins in electrotechnical products by means of solvent extraction and gas chromatography-negative chemical ionization-mass spectrometry (GC-NCI-MS).

This test method has been evaluated for use with ABS (acrylonitrile butadiene styrene) and PVC
 (polyvinyl chloride) containing individual SCCPs ranging from 369,7 mg/kg to 8653,9 mg/kg and MCCPs
 ranging from 2184 mg/kg to 27 329,6 mg/kg.

- 145 This standard is primarily intended for use by technical committees in the preparation of standards in 146 accordance with the principles laid down in IEC Guide 108.
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### 148 2 Normative references //standards.iteh.ai)

- The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.
- 152
   153 IEC 62321-1:2013, Determination of certain substances in electrotechnical products Part 1:
- 154 Introduction and overview
- IEC 62321-2, Determination of certain substances in electrotechnical products Part 2: Disassembly,
   disjointment and mechanical sample preparation
- 157 ISO 3696, Water for analytical laboratory use Specification and test methods
- 158 ISO 4787, Laboratory glassware Volumetric instruments Methods for testing of capacity and for
- 159 *use*
- 160

#### **161 3 Terms, definitions and abbreviated terms**

#### 162 3.1 Terms and definitions

- 163 For the purposes of this document, the terms and definitions provided in IEC 62321-1 apply.
- 164 ISO and IEC maintain terminological databases for use in standardization at the following addresses:
- 165 IEC Electropedia: available at http://www.electropedia.org/
- 166 ISO Online browsing platform: available at http://www.iso.org/obp